

Product Change Notification: ALAN-03HRHE038

Date:

05-Jun-2025

Product Category:

32-Bit Microcontrollers

Notification Subject:

CCB 6777 and 6777.002 Final Notice: Qualification of ANAP as an additional assembly location for selected ATSAM4N16C, ATSAM4N8C, ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4CA, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C, ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families available in 100L and 48L LQFP (14x14x1.4mm and 7x7x1.4mm) packages.

Affected CPNs:

ALAN-03HRHE038_Affected_CPN_06052025.pdf ALAN-03HRHE038 Affected CPN 06052025.csv

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ANAP as an additional assembly location for selected ATSAM4N16C, ATSAM4N8C, ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4C, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C, ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families available in 100L and 48L LQFP (14x14x1.4mm and 7x7x1.4mm) packages.

Pre and Post Summary Changes:

Applicable for ATSAM4N16C, ATSAM4N8C, ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4C, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C device families in 100L LQFP:

Pre Change	Post Change
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Assembly Site	Semiconductor		ATX Semicond (Shanghai (ASSH)		Amkor Technology Philippine (P1/P2), INC. (ANAP)						
Wire Material	CuPdAu	CuPd	CuPdAu CuPd		CuPdAu						
Die Attach Material	2288A		2288A		3230						
Molding Compound Material	CEL-9510	HFL	CEL-9510HFL		G631HQ						
Lead-Frame Material	C7025		C7025		C194ESH						
Lead-Frame Paddle Size	240X240	180X180	240X240	180X180	256X256						
Lead Lock	No		No		Yes						
See Pre and Post change for Lead	d-Frame Co	mparison.		See Pre and Post change for Lead-Frame Comparison.							

Applicable for ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families in 48L LQFP:

	Pre Change	Post Change					
Assembly Site	ATX Semiconductor (Shanghai)Co. Ltd (ASSH)	ATX Semiconductor (Shanghai)Co. Ltd (ASSH)	Amkor Technology Philippine (P1/P2), INC. (ANAP)				
Wire Material	CuPd	CuPd	CuPdAu				
Die Attach Material	2288A	2288A	3230				
Molding Compound Material	CEL-9510	CEL-9510	G631HQ				
Lead-Frame Material	C7025	C7025	C194ESH				
Lead-Frame Paddle Size	197X197	197X197	197X197				
See Pre and Post ch	ange for Lead-Frame Com	parison.					

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ANAP as an additional assembly site.

Change Implementation Status: In Progress

Estimated First Ship Date: 30 June 2025 (date code: 2527)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may

receive pre and post change parts.

Timetable Summary:

	January 2024				>	June 2025					
Work Week	1	2	3	4	5		23	24	25	26	27
Initial PCN Issue Date		X									
Qual Report Availability							х				
Final PCN Issue Date							х				
Estimated Implementation Date											X

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History: January 08, 2024: Issued initial notification.

April 10, 2024: Reissued the initial notification to include reference CCB 6777.002. Updated the Notification subject, Description of change and Pre and Post change summary table to include ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families. Updated the affected CPN list to include CPNs within the scope of CCB 6777.002. Updated Pre and Post Change summary to include lead frame drawing for 48L LQFP (7x7x1.4mm) package.

June 05, 2025: Issued final notification. Updated affected parts list to add ATSAM4SD16CB-AUR catalog part number. Attached the Qualification Report. Provided Estimated First Ship Date to be on June 30, 2025.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_ALAN-03HRHE038_Pre and Post Change Summary.pdf PCN_ALAN-03HRHE038_Qual Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> <u>home page</u> select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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Affected C	atalog Part	Numbers	(CPN)
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ATSAM4S8CA-AN

ATSAM4S8CA-ANR

ATSAM4SD16CB-AN

ATSAM4SD16CB-ANR

ATSAM4S8CB-AN

ATSAM4S8CB-ANR

ATSAM4SD32CB-AN

ATSAM4SD32CB-ANR

ATSAM4SD32CA-AU

ATSAM4SD32CA-AUR

ATSAM4S16CB-AN

ATSAM4S16CB-ANR

ATSAM4S16CA-AN

ATSAM4S16CA-ANR

ATSAM4S2CB-AN

ATSAM4S2CB-ANR

ATSAM4S16CA-AU

ATSAM4S16CA-AUR

ATSAM4SA16CA-AU

ATSAM4SA16CA-AUR

ATSAM4SA16CB-AN

ATSAM4SA16CB-ANR

ATSAM4S8CA-AU

ATSAM4S8CA-AUR

ATSAM4N8CA-AU

ATSAM4N8CA-AUR

ATSAM4N16CA-AU

Date: Wednesday, June 4, 2025

ALAN-03HRHE038 - CCB 6777 and 6777.002 Final Notice: Qualification of ANAP as an additional assembly location for selected ATSAM4N16C, ATSAM4N8C, ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4C, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C, ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families available in 100L and 48L LQFP (14x14x1.4mm and 7x7x1.4mm) packages.

ATSAM4N16CA-AUR	
ATSAM4S4CB-AN	
ATSAM4S4CB-ANR	
ATSAM4SD16CA-AU	
ATSAM4SD16CA-AUR	
ATSAM4SD16CB-AU	
ATSAM4SD16CB-AUR	
ATSAM4S4CA-AU	
ATSAM4S4CA-AUR	
ATSAM4S2CA-AU	
ATSAM4S4AB-AN	
ATSAM4S2AB-AN	
ATSAM4N8AA-AU	
ATSAM4S4AA-AU	
ATSAM4S2AA-AU	
ATSAM4N8AA-AUR	
ATSAM4S4AB-ANR	
ATSAM4S2AB-ANR	

Date: Wednesday, June 4, 2025

CCB 6777 and 6777.002 Pre and Post Change Summary PCN# ALAN-03HRHE038

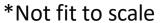


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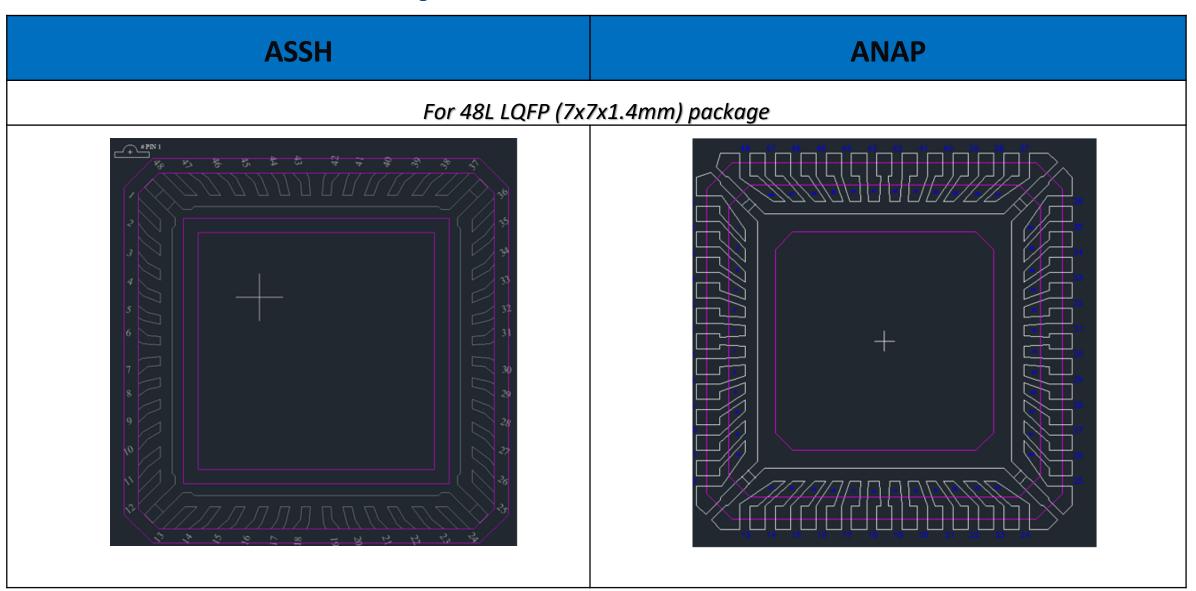
Lead-Frame Comparison

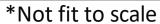
ASSH ANAP For 100L LQFP (14x14x1.4mm) package





Lead-Frame Comparison









QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: ALAN-03HRHE038

Date: May 6, 2025

Qualification of ANAP as an additional assembly location for selected ATSAM4N16C, ATSAM4N8C, ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4C, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C, ATSAM4S4A, ATSAM4S2A and ATSAM4N8A device families available in 100L and 48L LQFP (14x14x1.4mm and 7x7x1.4mm) packages.



Qualification of ANAP as an additional assembly location for selected ATSAM4N16C, ATSAM4N8C, Purpose:

> ATSAM4S16C, ATSAM4S16CA, ATSAM4S2C, ATSAM4S4C, ATSAM4S4CA, ATSAM4S8C, ATSAM4SA16C, ATSAM4SD16C, ATSAM4SD32C, ATSAM4S4A, ATSAM4S2A and ATSAM4N8A

device families available in 100L and 48L LQFP (14x14x1.4mm and 7x7x1.4mm) packages.

CCB No.: 6777 and 6777.002

	Assembly site	ANAP
Miss	BD Number	BD-002071-01
	MP Code (MPC)	63907TH7XC01
	Part Number (CPN)	ATSAM4SD32CA-AUR
Misc.	MSL information	MSL3
	Assembly Shipping Media (T/R, Tube/Tray)	Tray
	Base Quantity Multiple (BQM)	90/Tray
	Reliability Site	MPHIL
	Paddle size	256X256
	Material	C194ESH
	DAP Surface Prep	Double Ring Ag
	Treatment	Non-roughened
<u>Lead-</u>	Process	Stamped
<u>Frame</u>	Lead-lock	Yes
	Part Number	101423138
	Lead Plating	Matte Sn
	Strip Size	80x250mm
	Strip Density	UDLF
Bond Wire	Material	CuPdAu
	Part Number	3230
Die Attach	Conductive	Yes
MC	Part Number	G631HQ
	Package Type	LQFP
<u>PKG</u>	Pin/Ball Count	100
	PKG width/size	14x14x1.4mm



Manufacturing Information

Assembly Lot No.
ANAP244500078.000
ANAP244500079.000
ANAP244500080.000

Result	✓	Pass		Fail		
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63907 UMC 90nm in 100L LQFP 14x14x1.4mm assembled at ANAP pass Reliability test that was conducted at MPHL rel lab. This package is qualified Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks		
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test: 25°C D10I_UC 85°C D10I_UC	JESD22- A113, JIP/ IPC/JEDE C J-STD- 020E	231 per lot	Lot 1 0/231 Lot 2 0/231	Pass Pass	Good Devices		
	Bake 150°C, 24 hrs System: HERAEUS		231 per lot	Lot 3 0/231	Pass			
	Moisture Soak 192h(30°C/60%RH) System: VOTSCH VC4034		231 per lot					
	Reflow 3x Convection-Reflow 265°C max System: Mancorp CR.5000F		231 per lot	Lot 1 0/231	Pass			
				Lot 2 0/231 Lot 3	Pass Pass			
	Electrical Test: 25°C D10I_UC 85°C D10I_UC		231 per lot	0/231 Lot 1 0/231	Pass			
	00 C D101_0C			Lot 2 0/231	Pass			
				Lot 3 0/231	Pass			

	PACKAGE QUALIFIC	ATION	IREP	ORT		
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: HERAEUS	JESD22- A103	45 units 3 lots	Lot 1 0/45 Lot 2 0/45	Pass Pass	
	Electrical Test: 25°C D10I_UC 85°C D10I_UC			Lot 3 0/45	Pass	
HAST	Stress Condition: (Standard) 130°C, 85%RH, 96 hrs. VOLTS=3.3V System: HIRAYAMA HASTEST PC-422R8	JESD22- A110	77 units per lot	Lot 1 0/77 Lot 2 0/77		Parts had been pre-conditioned at 260°C
	Electrical Test: 25°C D10I_UC 85°C D10I_UC			Lot 3 0/77		
UNBIASED HAST	Stress Condition: (Standard) 130°C, 85%RH, 96 hrs. System: HIRAYAMA HASTEST PC-422R8	JESD22- A118	77 units per lot	Lot 1 0/77 Lot 2 0/77	Pass Pass	Parts had been pre-conditioned at 260°C
	Electrical Test: 25°C D10I_UC			Lot 3 0/77	Pass	

	PACKAGE QUA	LIFICAT	TION I	REPORT	•	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temp Cycle	Stress Condition: (Standard) - 65°C/150°C, 500 Cycles System: Votsch VTS²7012 Electrical Test: 85°C D10I_UC	JESD22- A104	77 units per lot	Lot 1 0/77 Lot 2 0/77 Lot 3 0/77	Pass Pass Pass	Parts had been pre- conditioned at 260°C
	Wire Bond Pull WBP	Mil. Std. 883- 2011	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Wire Bond Pull WBP, 0 Hour		Mil. Std. 883- 2011	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Wire Bond Shear WBS, 0Hour		CDF-AEC- Q100-001	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Standard Pb-free Solderability	>95% lead coverage	J-STD-002E	22 units 1 lot	0/22	Pass	